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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1176
Number of Logic Elements/Cells	5292
Total RAM Bits	57344
Number of I/O	284
Number of Gates	236666
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	456-BBGA
Supplier Device Package	456-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv200-4fg456c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Virtex Architecture

Virtex devices feature a flexible, regular architecture that comprises an array of configurable logic blocks (CLBs) surrounded by programmable input/output blocks (IOBs), all interconnected by a rich hierarchy of fast, versatile routing resources. The abundance of routing resources permits the Virtex family to accommodate even the largest and most complex designs.

Virtex FPGAs are SRAM-based, and are customized by loading configuration data into internal memory cells. In some modes, the FPGA reads its own configuration data from an external PROM (master serial mode). Otherwise, the configuration data is written into the FPGA (Select-MAPTM, slave serial, and JTAG modes).

The standard Xilinx Foundation™ and Alliance Series™ Development systems deliver complete design support for Virtex, covering every aspect from behavioral and schematic entry, through simulation, automatic design translation and implementation, to the creation, downloading, and readback of a configuration bit stream.

Higher Performance

Virtex devices provide better performance than previous generations of FPGA. Designs can achieve synchronous system clock rates up to 200 MHz including I/O. Virtex inputs and outputs comply fully with PCI specifications, and interfaces can be implemented that operate at 33 MHz or 66 MHz. Additionally, Virtex supports the hot-swapping requirements of Compact PCI.

Xilinx thoroughly benchmarked the Virtex family. While performance is design-dependent, many designs operated internally at speeds in excess of 100 MHz and can achieve 200 MHz. Table 2 shows performance data for representative circuits, using worst-case timing parameters.

Table 2: Performance for Common Circuit Functions

Function	Bits	Virtex -6
Register-to-Register		
Adder	16	5.0 ns
Audei	64	7.2 ns
Pipelined Multiplier	8 x 8	5.1 ns
	16 x 16	6.0 ns
Address Decoder	16	4.4 ns
	64	6.4 ns
16:1 Multiplexer		5.4 ns
Parity Tree	9	4.1 ns
	18	5.0 ns
	36	6.9 ns
Chip-to-Chip		
HSTL Class IV		200 MHz
LVTTL,16mA, fast slew		180 MHz

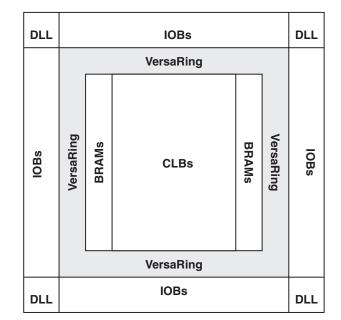


DS003-2 (v4.0) March 1, 2013

Virtex[™] 2.5 V Field Programmable Gate Arrays

Product Specification

The output buffer and all of the IOB control signals have independent polarity controls.



vao_b.eps

Figure 1: Virtex Architecture Overview

All pads are protected against damage from electrostatic discharge (ESD) and from over-voltage transients. Two forms of over-voltage protection are provided, one that permits 5 V compliance, and one that does not. For 5 V compliance, a Zener-like structure connected to ground turns on when the output rises to approximately 6.5 V. When PCI 3.3 V compliance is required, a conventional clamp diode is connected to the output supply voltage, $V_{\rm CCO}$.

Optional pull-up and pull-down resistors and an optional weak-keeper circuit are attached to each pad. Prior to configuration, all pins not involved in configuration are forced into their high-impedance state. The pull-down resistors and the weak-keeper circuits are inactive, but inputs can optionally be pulled up.

The activation of pull-up resistors prior to configuration is controlled on a global basis by the configuration mode pins. If the pull-up resistors are not activated, all the pins will float. Consequently, external pull-up or pull-down resistors must be provided on pins required to be at a well-defined logic level prior to configuration.

All Virtex IOBs support IEEE 1149.1-compatible boundary scan testing.

Architectural Description

Virtex Array

The Virtex user-programmable gate array, shown in Figure 1, comprises two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing logic
- IOBs provide the interface between the package pins and the CLBs

CLBs interconnect through a general routing matrix (GRM). The GRM comprises an array of routing switches located at the intersections of horizontal and vertical routing channels. Each CLB nests into a VersaBlock™ that also provides local routing resources to connect the CLB to the GRM.

The VersaRing[™] I/O interface provides additional routing resources around the periphery of the device. This routing improves I/O routability and facilitates pin locking.

The Virtex architecture also includes the following circuits that connect to the GRM.

- Dedicated block memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- 3-State buffers (BUFTs) associated with each CLB that drive dedicated segmentable horizontal routing resources

Values stored in static memory cells control the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

Input/Output Block

The Virtex IOB, Figure 2, features SelectIO™ inputs and outputs that support a wide variety of I/O signalling standards, see Table 1.

The three IOB storage elements function either as edge-triggered D-type flip-flops or as level sensitive latches. Each IOB has a clock signal (CLK) shared by the three flip-flops and independent clock enable signals for each flip-flop.

In addition to the CLK and CE control signals, the three flip-flops share a Set/Reset (SR). For each flip-flop, this signal can be independently configured as a synchronous Set, a synchronous Reset, an asynchronous Preset, or an asynchronous Clear.

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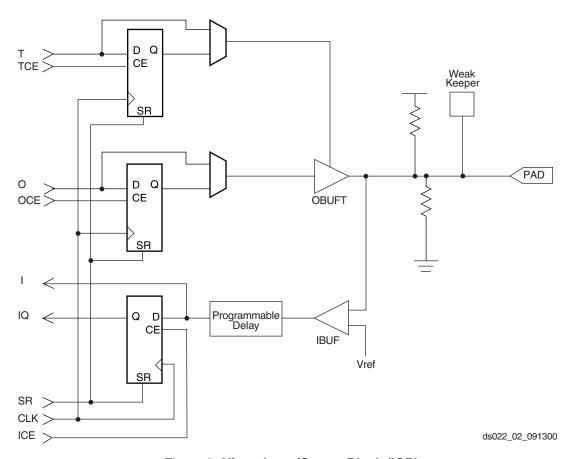


Figure 2: Virtex Input/Output Block (IOB)

Table 1: Supported Select I/O Standards

I/O Standard	Input Reference Voltage (V _{REF})	Output Source Voltage (V _{CCO})	Board Termination Voltage (V _{TT})	5 V Tolerant
LVTTL 2 – 24 mA	N/A	3.3	N/A	Yes
LVCMOS2	N/A	2.5	N/A	Yes
PCI, 5 V	N/A	3.3	N/A	Yes
PCI, 3.3 V	N/A	3.3	N/A	No
GTL	0.8	N/A	1.2	No
GTL+	1.0	N/A	1.5	No
HSTL Class I	0.75	1.5	0.75	No
HSTL Class III	0.9	1.5	1.5	No
HSTL Class IV	0.9	1.5	1.5	No
SSTL3 Class I &II	1.5	3.3	1.5	No
SSTL2 Class I & II	1.25	2.5	1.25	No
CTT	1.5	3.3	1.5	No
AGP	1.32	3.3	N/A	No



Input Path

A buffer In the Virtex IOB input path routes the input signal either directly to internal logic or through an optional input flip-flop.

An optional delay element at the D-input of this flip-flop eliminates pad-to-pad hold time. The delay is matched to the internal clock-distribution delay of the FPGA, and when used, assures that the pad-to-pad hold time is zero.

Each input buffer can be configured to conform to any of the low-voltage signalling standards supported. In some of these standards the input buffer utilizes a user-supplied threshold voltage, V_{REF}. The need to supply V_{REF} imposes constraints on which standards can used in close proximity to each other. See I/O Banking, page 3.

There are optional pull-up and pull-down resistors at each user I/O input for use after configuration. Their value is in the range 50 k Ω – 100 k Ω .

Output Path

The output path includes a 3-state output buffer that drives the output signal onto the pad. The output signal can be routed to the buffer directly from the internal logic or through an optional IOB output flip-flop.

The 3-state control of the output can also be routed directly from the internal logic or through a flip-flip that provides synchronous enable and disable.

Each output driver can be individually programmed for a wide range of low-voltage signalling standards. Each output buffer can source up to 24 mA and sink up to 48mA. Drive strength and slew rate controls minimize bus transients.

In most signalling standards, the output High voltage depends on an externally supplied V_{CCO} voltage. The need to supply V_{CCO} imposes constraints on which standards can be used in close proximity to each other. See **I/O Banking**, page 3.

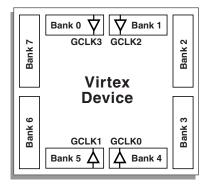
An optional weak-keeper circuit is connected to each output. When selected, the circuit monitors the voltage on the pad and weakly drives the pin High or Low to match the input signal. If the pin is connected to a multiple-source signal, the weak keeper holds the signal in its last state if all drivers are disabled. Maintaining a valid logic level in this way eliminates bus chatter.

Because the weak-keeper circuit uses the IOB input buffer to monitor the input level, an appropriate V_{REF} voltage must be provided if the signalling standard requires one. The provision of this voltage must comply with the I/O banking rules.

I/O Banking

Some of the I/O standards described above require V_{CCO} and/or V_{REF} voltages. These voltages externally and connected to device pins that serve groups of IOBs, called banks. Consequently, restrictions exist about which I/O standards can be combined within a given bank.

Eight I/O banks result from separating each edge of the FPGA into two banks, as shown in Figure 3. Each bank has multiple $V_{\rm CCO}$ pins, all of which must be connected to the same voltage. This voltage is determined by the output standards in use.



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Figure 3: Virtex I/O Banks

Within a bank, output standards can be mixed only if they use the same V_{CCO} . Compatible standards are shown in Table 2. GTL and GTL+ appear under all voltages because their open-drain outputs do not depend on V_{CCO} .

Table 2: Compatible Output Standards

V _{CCO}	Compatible Standards
3.3 V	PCI, LVTTL, SSTL3 I, SSTL3 II, CTT, AGP, GTL, GTL+
2.5 V	SSTL2 I, SSTL2 II, LVCMOS2, GTL, GTL+
1.5 V	HSTL I, HSTL III, HSTL IV, GTL, GTL+

Some input standards require a user-supplied threshold voltage, V_{REF} In this case, certain user-I/O pins are automatically configured as inputs for the V_{REF} voltage. Approximately one in six of the I/O pins in the bank assume this role

The V_{REF} pins within a bank are interconnected internally and consequently only one V_{REF} voltage can be used within each bank. All V_{REF} pins in the bank, however, must be connected to the external voltage source for correct operation.

Within a bank, inputs that require V_{REF} can be mixed with those that do not. However, only one V_{REF} voltage can be used within a bank. Input buffers that use V_{REF} are not 5 V tolerant. LVTTL, LVCMOS2, and PCI 33 MHz 5 V, are 5 V tolerant.

The V_{CCO} and V_{REF} pins for each bank appear in the device Pinout tables and diagrams. The diagrams also show the bank affiliation of each I/O.

Within a given package, the number of V_{REF} and V_{CCO} pins can vary depending on the size of device. In larger devices,



DC Characteristics Over Recommended Operating Conditions

Symbol	Description	1	Device	Min	Max	Units
V _{DRINT}	Data Retention V _{CCINT} Voltage		All	2.0		V
21	(below which configuration data can be	e lost)				
V_{DRIO}	Data Retention V _{CCO} Voltage (below which configuration data can be	e lost)	All	1.2		V
I _{CCINTQ}	Quiescent V _{CCINT} supply current ^(1,3)		XCV50		50	mA
			XCV100		50	mA
			XCV150		50	mA
			XCV200		75	mA
			XCV300		75	mA
			XCV400		75	mA
			XCV600		100	mA
			XCV800		100	mA
			XCV1000		100	mA
Iccoq	Quiescent V _{CCO} supply current ⁽¹⁾		XCV50		2	mA
			XCV100		2	mA
			XCV150		2	mA
			XCV200		2	mA
			XCV300		2	mA
			XCV400		2	mA
			XCV600		2	mA
			XCV800		2	mA
			XCV1000		2	mA
I _{REF}	V _{REF} current per V _{REF} pin		All		20	μΑ
ΙL	Input or output leakage current		All	-10	+10	μΑ
C _{IN}	Input capacitance (sample tested)	BGA, PQ, HQ, packages	All		8	pF
I _{RPU}	Pad pull-up (when selected) @ V _{in} = 0 tested)	V, V _{CCO} = 3.3 V (sample	All	Note (2)	0.25	mA
I _{RPD}	Pad pull-down (when selected) @ V _{in} =	= 3.6 V (sample tested)		Note (2)	0.15	mA

- 1. With no output current loads, no active input pull-up resistors, all I/O pins 3-stated and floating.
- 2. Internal pull-up and pull-down resistors guarantee valid logic levels at unconnected input pins. These pull-up and pull-down resistors do not guarantee valid logic levels when input pins are connected to other circuits.
- 3. Multiply I_{CCINTQ} limit by two for industrial grade.



Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device operation. The actual current consumed depends on the power-on ramp rate of the power supply. This is the time required to reach the nominal power supply voltage of the device⁽¹⁾ from 0 V. The current is highest at the fastest suggested ramp rate (0 V to nominal voltage in 2 ms) and is lowest at the slowest allowed ramp rate (0 V to nominal voltage in 50 ms). For more details on power supply requirements, see Application Note XAPP158 on www.xilinx.com.

Product	Description ⁽²⁾	Current Requirement ^(1,3)
Virtex Family, Commercial Grade	Minimum required current supply	500 mA
Virtex Family, Industrial Grade	Minimum required current supply	2 A

Notes:

- Ramp rate used for this specification is from 0 2.7 VDC. Peak current occurs on or near the internal power-on reset threshold of 1.0V and lasts for less than 3 ms.
- Devices are guaranteed to initialize properly with the minimum current available from the power supply as noted above.
- 3. Larger currents can result if ramp rates are forced to be faster.

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed output currents over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at minimum V_{CCO} for each standard with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Input/Output		V _{IL}	V _{IH}		V _{OL}	V _{OH}	I _{OL}	I _{OH}
Standard	V, min	V, max	V, min	V, max	V, Max	V, Min	mA	mA
LVTTL ⁽¹⁾	- 0.5	0.8	2.0	5.5	0.4	2.4	24	-24
LVCMOS2	- 0.5	.7	1.7	5.5	0.4	1.9	12	-12
PCI, 3.3 V	- 0.5	44% V _{CCINT}	60% V _{CCINT}	V _{CCO} + 0.5	10% V _{CCO}	90% V _{CCO}	Note 2	Note 2
PCI, 5.0 V	- 0.5	0.8	2.0	5.5	0.55	2.4	Note 2	Note 2
GTL	- 0.5	V _{REF} - 0.05	V _{REF} + 0.05	3.6	0.4	n/a	40	n/a
GTL+	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.6	n/a	36	n/a
HSTL I ⁽³⁾	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.4	V _{CCO} - 0.4	8	-8
HSTL III	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.4	V _{CCO} - 0.4	24	-8
HSTL IV	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.4	V _{CCO} - 0.4	48	-8
SSTL3 I	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.6	V _{REF} + 0.6	8	-8
SSTL3 II	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.8	V _{REF} + 0.8	16	-16
SSTL2 I	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.61	V _{REF} + 0.61	7.6	-7.6
SSTL2 II	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.80	V _{REF} + 0.80	15.2	-15.2
CTT	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.4	V _{REF} + 0.4	8	-8
AGP	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	10% V _{CCO}	90% V _{CCO}	Note 2	Note 2

- V_{OL} and V_{OH} for lower drive currents are sample tested.
- 2. Tested according to the relevant specifications.
- DC input and output levels for HSTL18 (HSTL I/O standard with V_{CCO} of 1.8 V) are provided in an HSTL white paper on www.xilinx.com.



IOB Output Switching Characteristics Standard Adjustments

Output delays terminating at a pad are specified for LVTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays by the values shown.

				Speed	Grade		Unit
Description	Symbol	Standard ⁽¹⁾	Min	-6	-5	-4	s
Output Delay Adjustments							
Standard-specific adjustments for	T _{OLVTTL_S2}	LVTTL, Slow, 2 mA	4.2	14.7	15.8	17.0	ns
output delays terminating at pads (based on standard capacitive load,	T _{OLVTTL_S4}	4 mA	2.5	7.5	8.0	8.6	ns
Csl)	T _{OLVTTL_S6}	6 mA	1.8	4.8	5.1	5.6	ns
	T _{OLVTTL_S8}	8 mA	1.2	3.0	3.3	3.5	ns
	T _{OLVTTL_S12}	12 mA	1.0	1.9	2.1	2.2	ns
	T _{OLVTTL_S16}	16 mA	0.9	1.7	1.9	2.0	ns
	T _{OLVTTL_S24}	24 mA	0.8	1.3	1.4	1.6	ns
	T _{OLVTTL_F2}	LVTTL, Fast, 2mA	1.9	13.1	14.0	15.1	ns
	T _{OLVTTL_F4}	4 mA	0.7	5.3	5.7	6.1	ns
	T _{OLVTTL_F6}	6 mA	0.2	3.1	3.3	3.6	ns
	T _{OLVTTL_F8}	8 mA	0.1	1.0	1.1	1.2	ns
	T _{OLVTTL_F12}	12 mA	0	0	0	0	ns
	T _{OLVTTL_F16}	16 mA	-0.10	-0.05	-0.05	-0.05	ns
	T _{OLVTTL_F24}	24 mA	-0.10	-0.20	-0.21	-0.23	ns
	T _{OLVCMOS2}	LVCMOS2	0.10	0.10	0.11	0.12	ns
	T _{OPCl33_3}	PCI, 33 MHz, 3.3 V	0.50	2.3	2.5	2.7	ns
	T _{OPCl33_5}	PCI, 33 MHz, 5.0 V	0.40	2.8	3.0	3.3	ns
	T _{OPCI66_3}	PCI, 66 MHz, 3.3 V	0.10	-0.40	-0.42	-0.46	ns
	T _{OGTL}	GTL	0.6	0.50	0.54	0.6	ns
	T _{OGTLP}	GTL+	0.7	0.8	0.9	1.0	ns
	T _{OHSTL_I}	HSTL I	0.10	-0.50	-0.53	-0.5	ns
	T _{OHSTL_III}	HSTL III	-0.10	-0.9	-0.9	-1.0	ns
	T _{OHSTL_IV}	HSTL IV	-0.20	-1.0	-1.0	-1.1	ns
	T _{OSSTL2_I}	SSTL2 I	-0.10	-0.50	-0.53	-0.5	ns
	T _{OSSLT2_II}	SSTL2 II	-0.20	-0.9	-0.9	-1.0	ns
	T _{OSSTL3_I}	SSTL3 I	-0.20	-0.50	-0.53	-0.5	ns
	T _{OSSTL3_II}	SSTL3 II	-0.30	-1.0	-1.0	-1.1	ns
	T _{OCTT}	CTT	0	-0.6	-0.6	-0.6	ns
	T _{OAGP}	AGP	0	-0.9	-0.9	-1.0	ns

^{1.} Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. For other I/O standards and different loads, see Table 2 and Table 3.



Clock Distribution Guidelines

			Speed Grade			
Description	Device	Symbol	-6	-5	-4	Units
Global Clock Skew ⁽¹⁾						
Global Clock Skew between IOB Flip-flops	XCV50	T _{GSKEWIOB}	0.10	0.12	0.14	ns, max
	XCV100		0.12	0.13	0.15	ns, max
	XCV150		0.12	0.13	0.15	ns, max
	XCV200		0.13	0.14	0.16	ns, max
	XCV300		0.14	0.16	0.18	ns, max
	XCV400		0.13	0.13	0.14	ns, max
	XCV600		0.14	0.15	0.17	ns, max
	XCV800		0.16	0.17	0.20	ns, max
	XCV1000		0.20	0.23	0.25	ns, max

Notes:

Clock Distribution Switching Characteristics

			Speed Grade			
Description	Symbol	Min	-6	- 5	-4	Units
GCLK IOB and Buffer						
Global Clock PAD to output.	T _{GPIO}	0.33	0.7	0.8	0.9	ns, max
Global Clock Buffer I input to O output	T _{GIO}	0.34	0.7	0.8	0.9	ns, max

^{1.} These clock-skew delays are provided for guidance only. They reflect the delays encountered in a typical design under worst-case conditions. Precise values for a particular design are provided by the timing analyzer.



CLB Switching Characteristics

Delays originating at F/G inputs vary slightly according to the input used. The values listed below are worst-case. Precise values are provided by the timing analyzer.

		Speed Grade				
Description	Symbol	Min	-6	-5	-4	Units
Combinatorial Delays		•				
4-input function: F/G inputs to X/Y outputs	T _{ILO}	0.29	0.6	0.7	0.8	ns, max
5-input function: F/G inputs to F5 output	T _{IF5}	0.32	0.7	0.8	0.9	ns, max
5-input function: F/G inputs to X output	T _{IF5X}	0.36	0.8	0.8	1.0	ns, max
6-input function: F/G inputs to Y output via F6 MUX	T _{IF6Y}	0.44	0.9	1.0	1.2	ns, max
6-input function: F5IN input to Y output	T _{F5INY}	0.17	0.32	0.36	0.42	ns, max
Incremental delay routing through transparent latch to XQ/YQ outputs	T _{IFNCTL}	0.31	0.7	0.7	0.8	ns, max
BY input to YB output	T _{BYYB}	0.27	0.53	0.6	0.7	ns, max
Sequential Delays						T.
FF Clock CLK to XQ/YQ outputs	T _{CKO}	0.54	1.1	1.2	1.4	ns, max
Latch Clock CLK to XQ/YQ outputs	T _{CKLO}	0.6	1.2	1.4	1.6	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾		Setup T	ime / Hol	d Time		
4-input function: F/G Inputs	T _{ICK} /T _{CKI}	0.6 / 0	1.2 / 0	1.4 / 0	1.5 / 0	ns, min
5-input function: F/G inputs	T _{IF5CK} /T _{CKIF5}	0.7 / 0	1.3 / 0	1.5 / 0	1.7 / 0	ns, min
6-input function: F5IN input	T _{F5INCK} /T _{CKF5IN}	0.46 / 0	1.0 / 0	1.1 / 0	1.2 / 0	ns, min
6-input function: F/G inputs via F6 MUX	T _{IF6CK} /T _{CKIF6}	0.8 / 0	1.5 / 0	1.7 / 0	1.9 / 0	ns, min
BX/BY inputs	T_{DICK}/T_{CKDI}	0.30 / 0	0.6 / 0	0.7 / 0	0.8 / 0	ns, min
CE input	T_{CECK}/T_{CKCE}	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR/BY inputs (synchronous)	$T_{RCK}T_{CKR}$	0.33 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T _{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T_CL	0.8	1.5	1.7	2.0	ns, min
Set/Reset						
Minimum Pulse Width, SR/BY inputs	T _{RPW}	1.3	2.5	2.8	3.3	ns, min
Delay from SR/BY inputs to XQ/YQ outputs (asynchronous)	T _{RQ}	0.54	1.1	1.3	1.4	ns, max
Delay from GSR to XQ/YQ outputs	T _{IOGSRQ}	4.9	9.7	10.9	12.5	ns, max
Toggle Frequency (MHz) (for export control)	F _{TOG} (MHz)	625	333	294	250	MHz

^{1.} A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



CLB SelectRAM Switching Characteristics

		Speed Grade				
Description	Symbol	Min	-6	-5	-4	Units
Sequential Delays						
Clock CLK to X/Y outputs (WE active) 16 x 1 mode	T _{SHCKO16}	1.2	2.3	2.6	3.0	ns, max
Clock CLK to X/Y outputs (WE active) 32 x 1 mode	T _{SHCKO32}	1.2	2.7	3.1	3.5	ns, max
Shift-Register Mode						
Clock CLK to X/Y outputs	T _{REG}	1.2	3.7	4.1	4.7	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾		Se	tup Time /	Hold Time	T.	·
F/G address inputs	T _{AS} /T _{AH}	0.25 / 0	0.5 / 0	0.6 / 0	0.7 / 0	ns, min
BX/BY data inputs (DIN)	T _{DS} /T _{DH}	0.34 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
CE input (WE)	T _{WS} /T _{WH}	0.38 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
Shift-Register Mode		1		,	·	1
BX/BY data inputs (DIN)	T _{SHDICK}	0.34	0.7	0.8	0.9	ns, min
CE input (WS)	T _{SHCECK}	0.38	0.8	0.9	1.0	ns, min
Clock CLK		-			1	1
Minimum Pulse Width, High	T _{WPH}	1.2	2.4	2.7	3.1	ns, min
Minimum Pulse Width, Low	T _{WPL}	1.2	2.4	2.7	3.1	ns, min
Minimum clock period to meet address write cycle time	T _{WC}	2.4	4.8	5.4	6.2	ns, min
Shift-Register Mode						
Minimum Pulse Width, High	T _{SRPH}	1.2	2.4	2.7	3.1	ns, min
Minimum Pulse Width, Low	T _{SRPL}	1.2	2.4	2.7	3.1	ns, min

^{1.} A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



Block RAM Switching Characteristics

	Speed Grade					
Description	Symbol	Min	-6	-5	-4	Units
Sequential Delays						
Clock CLK to DOUT output	T _{BCKO}	1.7	3.4	3.8	4.3	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾		Setu	p Time / H	old Time		
ADDR inputs	T _{BACK} /T _{BCKA}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
DIN inputs	T _{BDCK} /T _{BCKD}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
EN input	T _{BECK} /T _{BCKE}	1.3 / 0	2.6 / 0	3.0 / 0	3.4 / 0	ns, min
RST input	T _{BRCK} /T _{BCKR}	1.3 / 0	2.5 / 0	2.7 / 0	3.2 / 0	ns, min
WEN input	T _{BWCK} /T _{BCKW}	1.2 / 0	2.3 / 0	2.6 / 0	3.0 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T _{BPWH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T _{BPWL}	0.8	1.5	1.7	2.0	ns, min
CLKA -> CLKB setup time for different ports	T _{BCCS}		3.0	3.5	4.0	ns, min

Notes:

TBUF Switching Characteristics

		Speed Grade				
Description	Symbol	Min	-6	-5	-4	Units
Combinatorial Delays						
IN input to OUT output	T _{IO}	0	0	0	0	ns, max
TRI input to OUT output high-impedance	T _{OFF}	0.05	0.09	0.10	0.11	ns, max
TRI input to valid data on OUT output	T _{ON}	0.05	0.09	0.10	0.11	ns, max

JTAG Test Access Port Switching Characteristics

		Speed Grade			
Description	Symbol	-6	-5	-4	Units
TMS and TDI Setup times before TCK	T _{TAPTCK}	4.0	4.0	4.0	ns, min
TMS and TDI Hold times after TCK	T _{TCKTAP}	2.0	2.0	2.0	ns, min
Output delay from clock TCK to output TDO	T _{TCKTDO}	11.0	11.0	11.0	ns, max
Maximum TCK clock frequency	F _{TCK}	33	33	33	MHz, max

^{1.} A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



Virtex Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Listed below are representative values for typical pin locations and normal clock loading. Values are expressed in nanoseconds unless otherwise noted

Global Clock Set-Up and Hold for LVTTL Standard, with DLL

			Speed Grade							
Description	Symbol	Device	Min	-6	-5	-4	Units			
	Input Setup and Hold Time Relative to Global Clock Input Signal for LVTTL Standard. For data input with different standards, adjust the setup time delay by the values shown in Input Delay Adjustments.									
No Delay Global Clock and IFF, with DLL	T _{PSDLL} /T _{PHDLL}	XCV50	0.40 / -0.4	1.7 /-0.4	1.8 /0.4	2.1 /-0.4	ns, min			
		XCV100	0.40 /0.4	1.7 /-0.4	1.9 /0.4	2.1 /-0.4	ns, min			
		XCV150	0.40 /0.4	1.7 /-0.4	1.9 /0.4	2.1 /-0.4	ns, min			
		XCV200	0.40 /0.4	1.7 /-0.4	1.9 /0.4	2.1 /-0.4	ns, min			
		XCV300	0.40 /0.4	1.7 /-0.4	1.9 /0.4	2.1 /-0.4	ns, min			
		XCV400	0.40 /0.4	1.7 /-0.4	1.9 /0.4	2.1 /-0.4	ns, min			
		XCV600	0.40 /0.4	1.7 /-0.4	1.9 /0.4	2.1 /-0.4	ns, min			
		XCV800	0.40 /-0.4	1.7 /-0.4	1.9 /-0.4	2.1 /-0.4	ns, min			
		XCV1000	0.40 /-0.4	1.7 /-0.4	1.9 /0.4	2.1 /-0.4	ns, min			

IFF = Input Flip-Flop or Latch

- 2. DLL output jitter is already included in the timing calculation.
- 3. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

^{1.} Set-up time is measured relative to the Global Clock input signal with the fastest route and the lightest load. Hold time is measured relative to the Global Clock input signal with the slowest route and heaviest load.



Period Tolerance: the allowed input clock period change in nanoseconds.

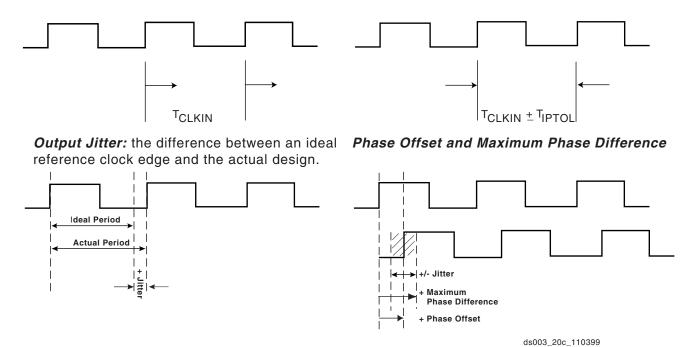


Figure 1: Frequency Tolerance and Clock Jitter

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.



Virtex Pinout Information

Pinout Tables

See www.xilinx.com for updates or additional pinout information. For convenience, Table 2, Table 3 and Table 4 list the locations of special-purpose and power-supply pins. Pins not listed are either user I/Os or not connected, depending on the device/package combination. See the Pinout Diagrams starting on page 17 for any pins not listed for a particular part/package combination.

Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages)

Pin Name	Device	CS144	TQ144	PQ/HQ240
GCK0	All	K7	90	92
GCK1	All	M7	93	89
GCK2	All	A7	19	210
GCK3	All	A6	16	213
MO	All	M1	110	60
M1	All	L2	112	58
M2	All	N2	108	62
CCLK	All	B13	38	179
PROGRAM	All	L12	72	122
DONE	All	M12	74	120
INIT	All	L13	71	123
BUSY/DOUT	All	C11	39	178
D0/DIN	All	C12	40	177
D1	All	E10	45	167
D2	All	E12	47	163
D3	All	F11	51	156
D4	All	H12	59	145
D5	All	J13	63	138
D6	All	J11	65	134
D7	All	K10	70	124
WRITE	All	C10	32	185
CS	All	D10	33	184
TDI	All	A11	34	183
TDO	All	A12	36	181
TMS	All	B1	143	2
TCK	All	C3	2	239
V _{CCINT}	All	A9, B6, C5, G3, G12, M5, M9, N6	10, 15, 25, 57, 84, 94, 99, 126	16, 32, 43, 77, 88, 104, 137, 148, 164, 198, 214, 225



Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

Pin Name	Device	CS144	TQ144	PQ/HQ240
V _{REF} , Bank 6	XCV50	H2, K1	116, 123	36, 50
(V _{REF} pins are listed	XCV100/150	+ J3	+ 118	+ 47
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 54
the required device	XCV400	N/A	N/A	+ 33
and all smaller devices listed in the same	XCV600	N/A	N/A	+ 48
package.)	XCV800	N/A	N/A	+ 40
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
V _{REF} , Bank 7	XCV50	D4, E1	133, 140	9, 23
(V _{REF} pins are listed	XCV100/150	+ D2	+ 138	+ 12
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 5
the required device	XCV400	N/A	N/A	+ 26
and all smaller devices listed in the same	XCV600	N/A	N/A	+ 11
package.)	XCV800	N/A	N/A	+ 19
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
GND	All	A1, B9, B11, C7, D5, E4, E11, F1, G10, J1, J12, L3, L5, L7, L9, N12	9, 18, 26, 35, 46, 54, 64, 75, 83, 91, 100, 111, 120, 129, 136, 144,	1, 8, 14, 22, 29, 37, 45, 51, 59, 69, 75, 83, 91, 98, 106, 112, 119, 129, 135, 143, 151, 158, 166, 172, 182, 190, 196, 204, 211, 219, 227, 233



Table 3: Virtex Pinout Tables (BGA) (Continued)

Pin Name	Device	BG256	BG352	BG432	BG560
V _{CCO} , Bank 7	All	G4, H4	G23, K26, N23	A31, L28, L31	C32, D33, K33, N32, T33
V _{REF} , Bank 0	XCV50	A8, B4	N/A	N/A	N/A
(VREF pins are listed incrementally. Connect all	XCV100/150	+ A4	A16,C19, C21	N/A	N/A
pins listed for both the required device and all smaller devices listed in the	XCV200/300	+ A2	+ D21	B19, D22, D24, D26	N/A
same package.)	XCV400	N/A	N/A	+ C18	A19, D20,
Within each bank, if input					D26, E23, E27
reference voltage is not required, all V _{REF} pins are	XCV600	N/A	N/A	+ C24	+ E24
general I/O.	XCV800	N/A	N/A	+ B21	+ E21
	XCV1000	N/A	N/A	N/A	+ D29
V _{REF} , Bank 1	XCV50	A17, B12	N/A	N/A	N/A
(VREF pins are listed incrementally. Connect all	XCV100/150	+ B15	B6, C9, C12	N/A	N/A
pins listed for both the required device and all smaller devices listed in the	XCV200/300	+ B17	+ D6	A13, B7, C6, C10	N/A
same package.) Within each bank, if input reference voltage is not	XCV400	N/A	N/A	+ B15	A6, D7, D11, D16, E15
required, all V _{REF} pins are	XCV600	N/A	N/A	+ D10	+ D10
general I/O.	XCV800	N/A	N/A	+ B12	+ D13
	XCV1000	N/A	N/A	N/A	+ E7
V _{REF} , Bank 2	XCV50	C20, J18	N/A	N/A	N/A
(V _{REF} pins are listed incrementally. Connect all pins listed for both the	XCV100/150	+ F19	E2, H2, M4	N/A	N/A
required device and all smaller devices listed in the	XCV200/300	+ G18	+ D2	E2, G3, J2, N1	N/A
same package.)	XCV400	N/A	N/A	+ R3	G5, H4,
Within each bank, if input reference voltage is not					L5, P4, R1
required, all V _{REF} pins are	XCV600	N/A	N/A	+ H1	+ K5
general I/O.	XCV800	N/A	N/A	+ M3	+ N5
	XCV1000	N/A	N/A	N/A	+ B3

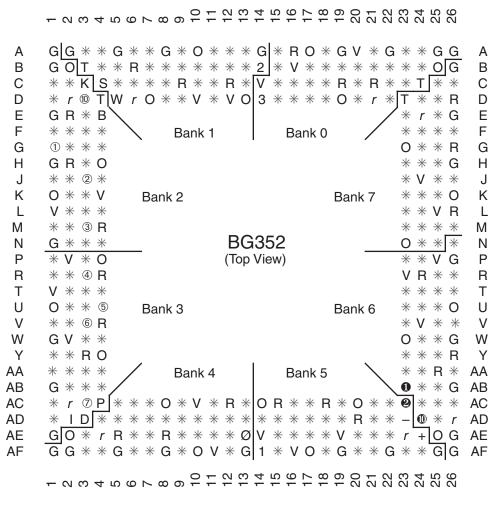


Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
V _{REF} Bank 4	XCV50	P9, T12	N/A	N/A	N/A
(V _{REF} pins are listed incrementally. Connect	XCV100/150	+ T11	AA13, AB16, AB19	N/A	N/A
all pins listed for both the required device and	XCV200/300	+ R13	+ AB20	N/A	N/A
all smaller devices listed in the same package.)	XCV400	N/A	N/A	AC15, AD18, AD21, AD22, AF15	N/A
Within each bank, if input reference voltage is not required, all V _{REF}	XCV600	N/A	N/A	+ AF20	AT19, AU7, AU17, AV8, AV10, AW11
pins are general I/O.	XCV800	N/A	N/A	+ AF17	+ AV14
	XCV1000	N/A	N/A	N/A	+ AU6
V _{REF} Bank 5	XCV50	T4, P8	N/A	N/A	N/A
(V _{REF} pins are listed	XCV100/150	+ R5	W8, Y10, AA5	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ T2	+ Y6	N/A	N/A
the required device and all smaller devices	XCV400	N/A	N/A	AA10, AB8, AB12, AC7, AF12	N/A
listed in the same package.) Within each bank, if	XCV600	N/A	N/A	+ AF8	AT27, AU29, AU31, AV35, AW21, AW23
input reference voltage is not required, all V _{REF}	XCV800	N/A	N/A	+ AE10	+ AT25
pins are general I/O.	XCV1000	N/A	N/A	N/A	+ AV36
V _{REF} Bank 6	XCV50	J3, N1	N/A	N/A	N/A
(V _{REF} pins are listed	XCV100/150	+ M1	N2, R4, T3	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ N2	+ Y1	N/A	N/A
the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage	XCV400	N/A	N/A	AB3, R1, R4, U6, V5	N/A
	XCV600	N/A	N/A	+ Y1	AB35, AD37, AH39, AK39, AM39, AN36
is not required, all V _{REF}	XCV800	N/A	N/A	+ U2	+ AE39
pins are general I/O.	XCV1000	N/A	N/A	N/A	+ AT39



BG352 Pin Function Diagram



DS003_19_100600

Figure 5: BG352 Pin Function Diagram



FG256 Pin Function Diagram

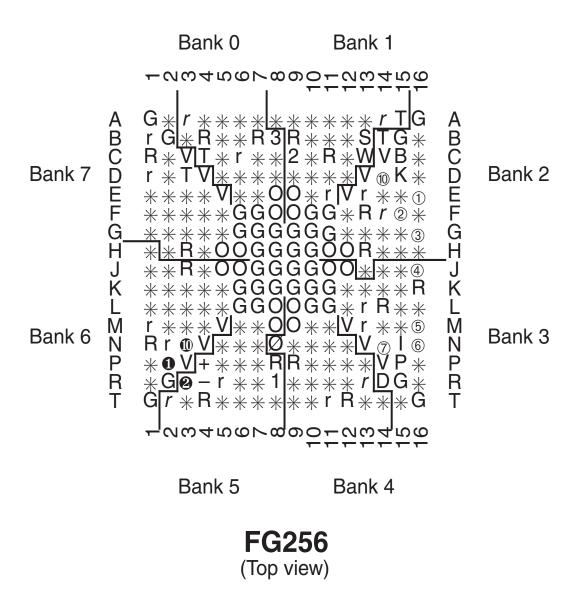
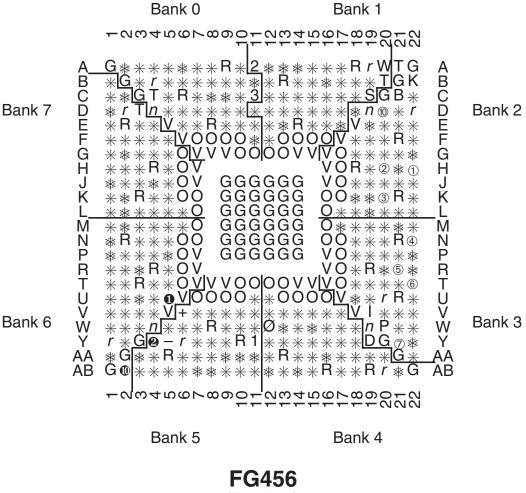


Figure 8: FG256 Pin Function Diagram



FG456 Pin Function Diagram



(Top view)

Figure 9: FG456 Pin Function Diagram

Notes:

Packages FG456 and FG676 are layout compatible.